

Supporting Information

Nonuniform Functional Group Distribution of Carbon Nanotubes Studied by Energy Dispersive X-ray Spectrometry Imaging in SEM

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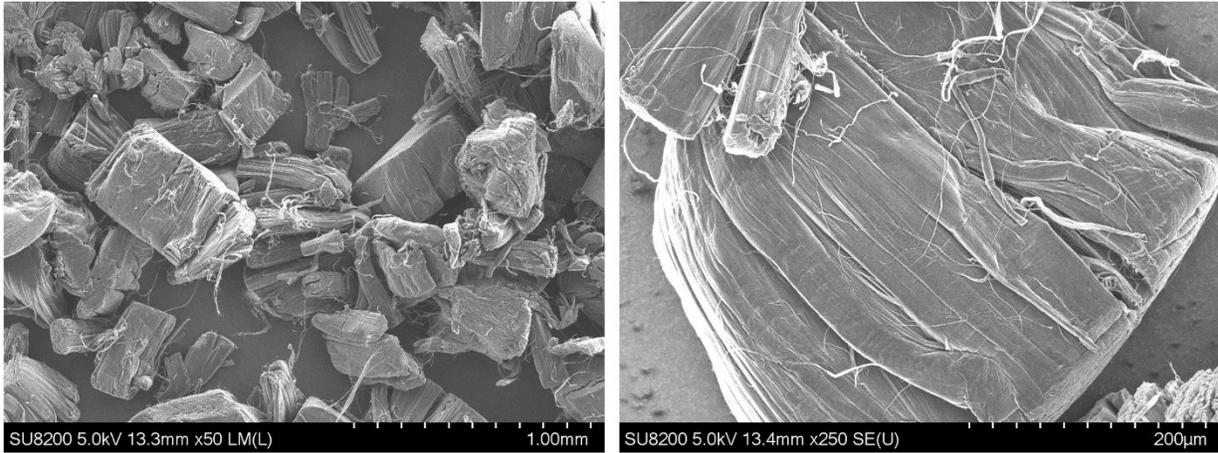


Figure S1. SEM images of as-grown super-growth SWCNT forests.

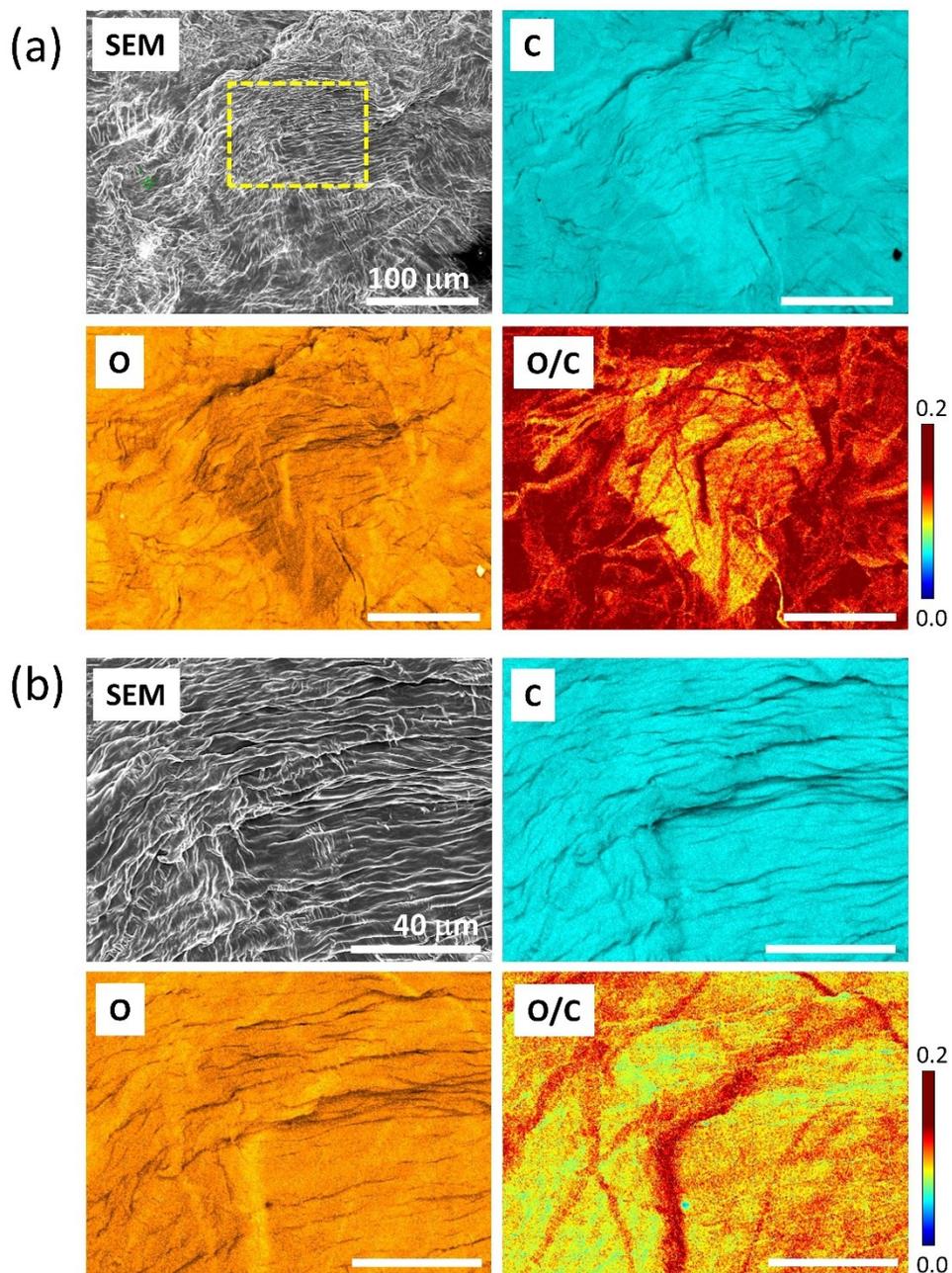


Figure S2. SEM-EDS images of $\text{KMnO}_4/\text{H}_2\text{SO}_4$ buckypaper at (a) low magnification (x350). A forest-like structure appears in the O/C image. (b) corresponds to an expanded view the area inside the yellow dashed line in (a) at a magnification of x 1,000.

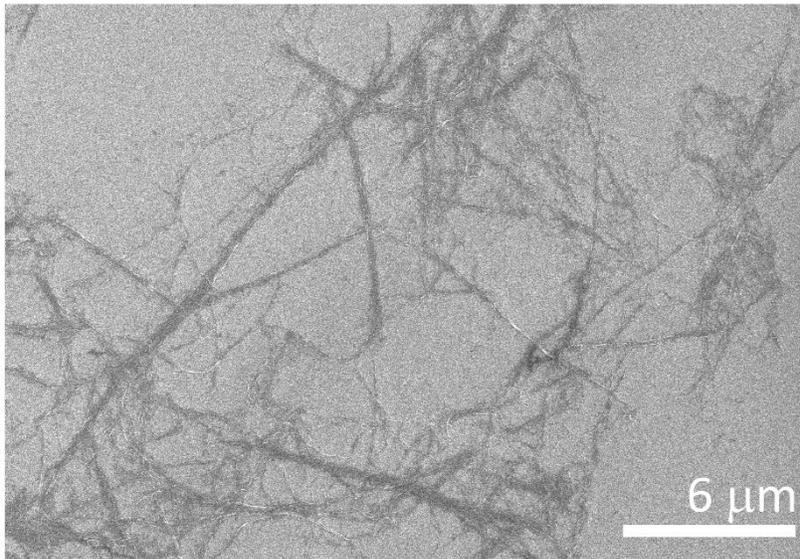


Figure S3. SEM image of $\text{KMnO}_4/\text{H}_2\text{SO}_4$ -treated SWCNTs transferred onto Si substrate.

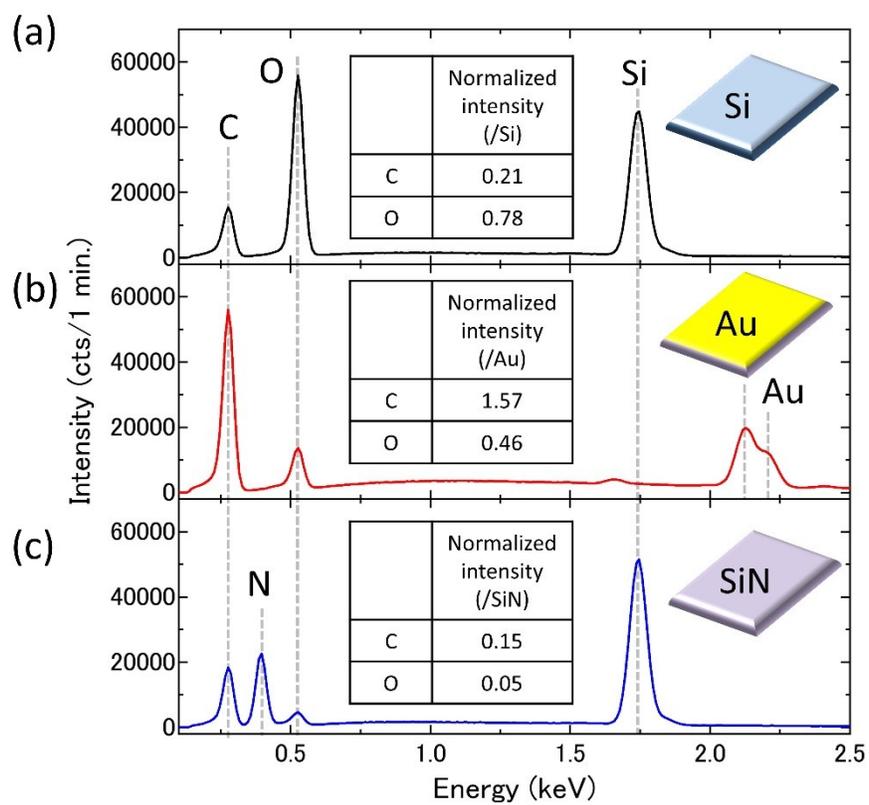


Figure S4. EDS spectra from (a) Si, (b) Au, and (c) Si₃N₄ substrate. The inset tables indicate normalized intensities of C and O components from each corresponding substrate. By using a Si₃N₄ substrate, oxygen generation is much suppressed as low as < 0.1 atm%.

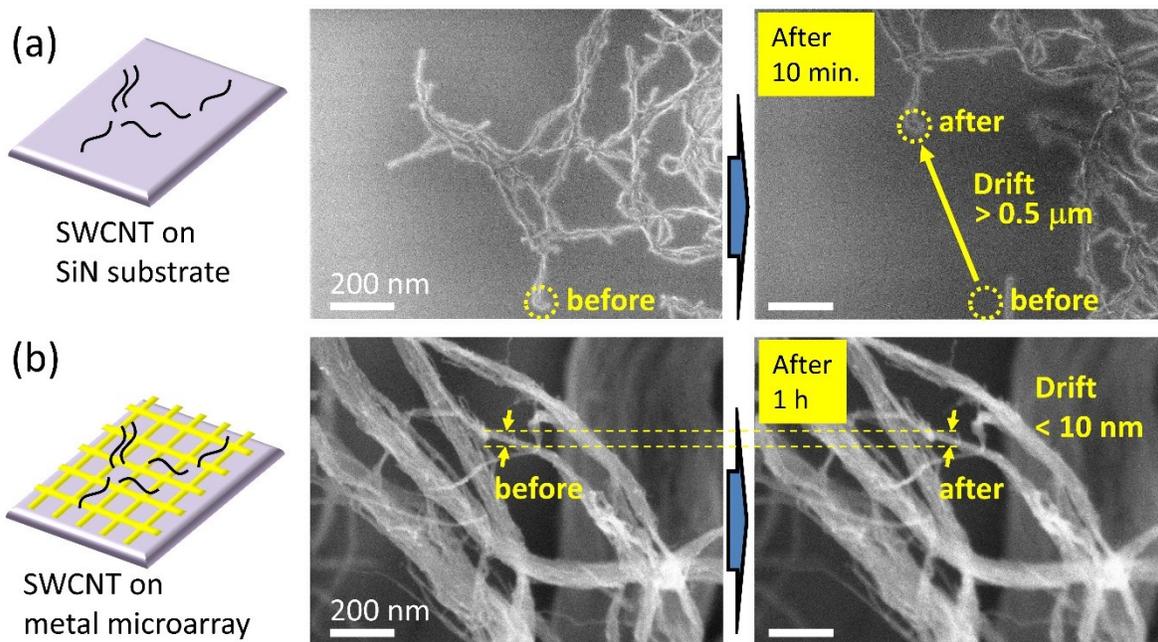


Figure S5. Monitoring the SEM measurement of SWCNT on Si_3N_4 substrate (a) without and (b) with a patterning metal microarray. (a) Significant imaging drift was observed due to the effect of charging by electron-beam irradiation. (b) Drift is suppressed by using a metal microarray during 1 hour of observation.

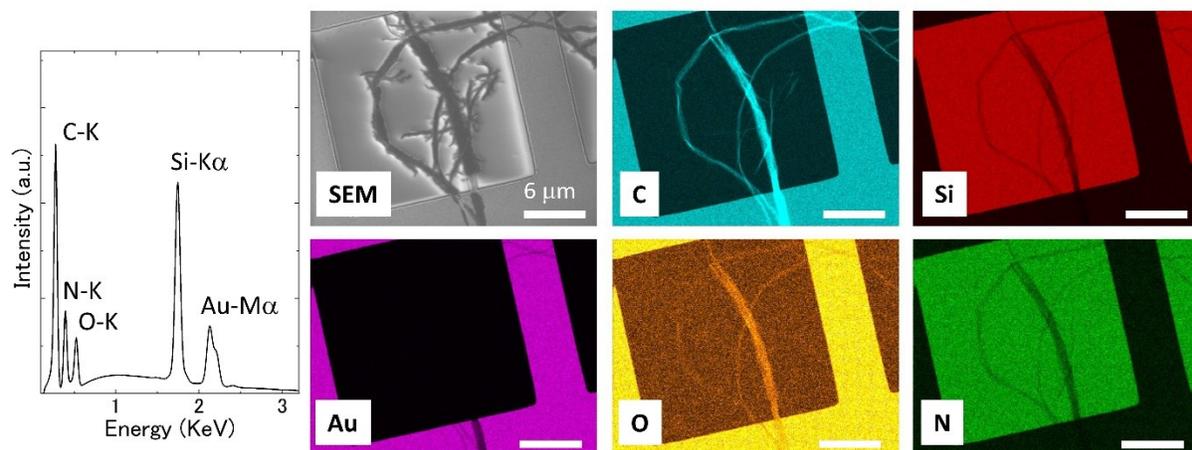
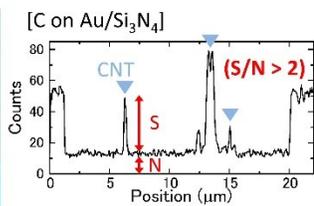
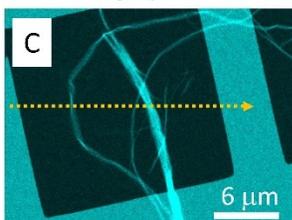


Figure S6. EDS images of SWCNT bundle structures on metal-microarray/ Si_3N_4 substrate. The results are for SEM, C, Si, Au, O, and N. The left figure indicates the obtained EDS spectrum.

(a) Au/Si₃N₄ substrate



(b) Si substrate

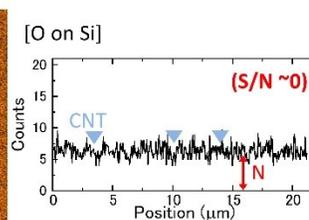
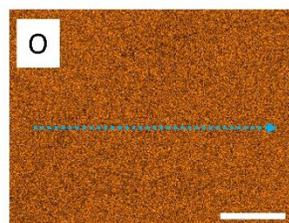
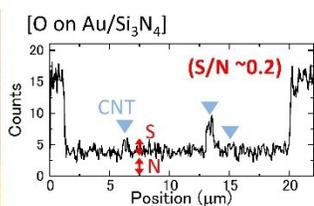
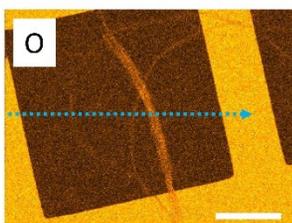
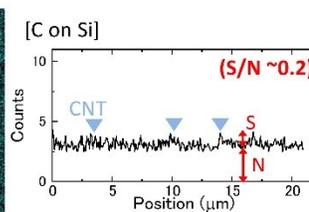
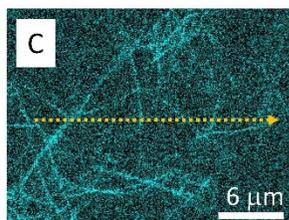


Figure S7. Result of line profile analysis of EDS imaging with (a) a metal-microarray on Si₃N₄ substrate (Figure 4d) and a Si substrate (Figure 4b). The estimated S/N ratio of imaging contrast are also listed. Here, we defined the S/N ratio as signal intensity divided by noise intensity.

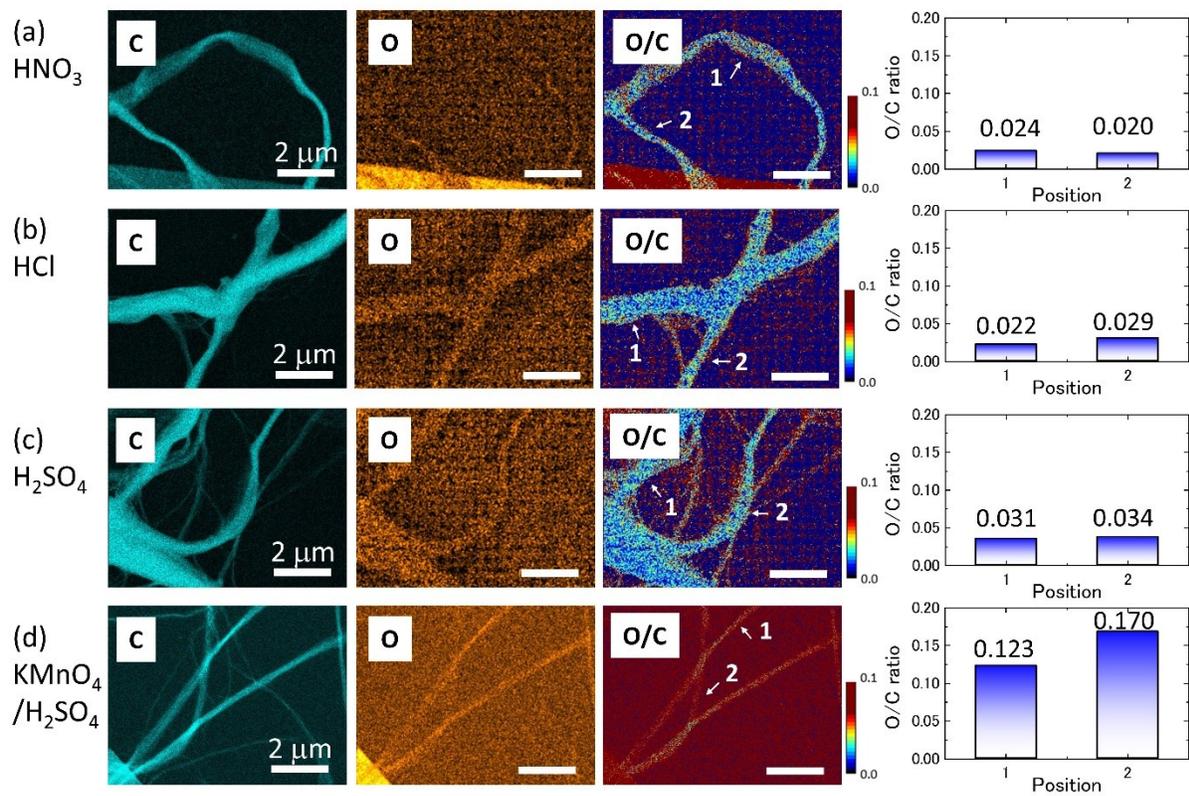


Figure S8. EDS imaging results with metal-microarray/Si₃N₄ substrate for each SWCNT sample.